onsemi

Silicon Carbide (SiC) MOSFET – EliteSiC, 20 mohm, 900 V, M2, D2PAK-7L

NTBG020N090SC1

Features

- Typ. $R_{DS(on)} = 20 \text{ m}\Omega @ V_{GS} = 15 \text{ V}$
- Typ. $R_{DS(on)} = 16 \text{ m}\Omega @ V_{GS} = 18 \text{ V}$
- Ultra Low Gate Charge ($Q_{G(tot)} = 200 \text{ nC}$)
- Low Effective Output Capacitance (Coss = 295 pF)
- 100% Avalanche Tested
- This Device is Halide Free and RoHS Compliant with exemption 7a, Pb–Free 2LI (on second level interconnection)

Typical Applications

- UPS
- DC-DC Converter
- Boost Inverter

MAXIMUM RATINGS (T_J = 25° C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			V _{DSS}	900	V
Gate-to-Source Voltag	je		V _{GS}	+22/-8	V
Recommended Operat Values of Gate-Source		T _C < 175°C	V _{GSop}	+15/–5	V
$\begin{array}{l} \text{Continuous Drain} \\ \text{Current } R_{\theta JC} \\ \text{(Note 2)} \end{array}$	Steady State	T _C = 25°C	Ι _D	112	A
Power Dissipation $R_{\theta JC}$ (Note 2)			P _D	477	W
Continuous Drain Current $R_{\theta JA}$ (Notes 1, 2)	Steady State	T _A = 25°C	Ι _D	9.8	A
Power Dissipation $R_{\theta JA}$ (Notes 1, 2)			PD	3.7	W
Pulsed Drain Current (Note 3)	T _A = 25°C	I _{DM}	448	А
Operating Junction and Storage Temperature Range			T _J , T _{stg}	–55 to +175	°C
Source Current (Body	Source Current (Body Diode)		I _S	148	А
Single Pulse Drain-to-Source Avalanche Energy ($I_L = 23 A_{pk}$, L = 1 mH) (Note 4)		E _{AS}	264	mJ	
Maximum Lead Tempe 1/8" from Case for 10 \$		oldering,	ΤL	245	°C
Ctropped avecading the					

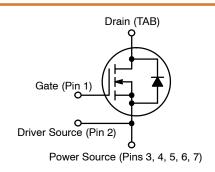
Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Surface mounted on a FR-4 board using1 in² pad of 2 oz copper.

 The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
Repetitive rating, limited by max junction temperature.

4. E_{AS} of 264 mJ is based on starting $T_J = 25^{\circ}$ C; L = 1 mH, $I_{AS} = 23$ A, $V_{DD} = 100$ V, $V_{GS} = 15$ V.

V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
900 V	28 mΩ @ 15 V	112 A





D2PAK-7L CASE 418BJ N-CHANNEL MOSFET

MARKING DIAGRAM



A = Assembly Location

- Y = Year
- WW = Work Week
- ZZ = Lot Traceability
- NTBG020N090SC1 = Specific Device Code

ORDERING INFORMATION

Device	Package	Shipping [†]
NTBG020N090SC1	D2PAK-7L	800 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, <u>BRD8011/D</u>.

Table 1. THERMAL CHARACTERISTICS

Parameter	Symbol	Мах	Unit
Thermal Resistance Junction-to-Case (Note 2)	$R_{ extsf{ heta}JC}$	0.31	°C/W
Thermal Resistance Junction-to-Ambient (Notes 1, 2)	$R_{ extsf{ heta}JA}$	41	°C/W

Table 2. ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise stated)

Parameter	Symbol	Test	Condition	Min	Тур	Max	Unit
OFF CHARACTERISTICS		•			•		
Drain-to-Source Breakdown Voltage	V _{(BR)DSS}	V_{GS} = 0 V, I _D =	1 mA	900			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V _{(BR)DSS} /T _J	I _D = 1 mA, refe	r to 25°C		440		mV/°C
Zero Gate Voltage Drain Current	I _{DSS}	V _{GS} = 0 V,	$T_J = 25^{\circ}C$			100	μA
		V _{DS} = 900 V	T _J = 175°C			250	μA
Gate-to-Source Leakage Current	I _{GSS}	$V_{GS} = +22/-8$ \	/, V _{DS} = 0 V			±1	μA
ON CHARACTERISTICS		•		•			
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}$, I_D	= 20 mA	1.8	2.6	4.3	V
Recommended Gate Voltage	V _{GOP}			-5		+15	V
Drain-to-Source On Resistance	R _{DS(on)}	V_{GS} = 15 V, I_D = 60 A, T_J = 25°C			20	28	mΩ
		V _{GS} = 18 V, I _D	= 60 A, T _J = 25°C		16		
		$V_{GS} = 15 \text{ V}, \text{ I}_{D} = 60 \text{ A},$	= 60 A, T _J = 175°C		27		
Forward Transconductance	9 _{FS}	$V_{DS} = 20 \text{ V}, \text{ I}_{D} =$	= 60 A		49		S
CHARGES, CAPACITANCES & GATE RI	ESISTANCE	1			•		
Input Capacitance	C _{ISS}	V _{GS} = 0 V, f = 1 MHz,			4415		pF
Output Capacitance	C _{OSS}	V _{DS} = 450 V			295		
Reverse Transfer Capacitance	C _{RSS}				25		
Total Gate Charge	Q _{G(TOT)}	V _{GS} = -5/15 V,	V _{DS} = 720 V,		200		nC
Threshold Gate Charge	Q _{G(TH)}	I _D = 60 A			42		
Gate-to-Source Charge	Q _{GS}				76		
Gate-to-Drain Charge	Q _{GD}				56		
Gate-Resistance	R _G	f = 1 MHz			1.5		Ω
SWITCHING CHARACTERISTICS		•		•	•	•	
Turn–On Delay Time	t _{d(ON)}	$V_{GS} = -5/15 V_{,}$	V _{DS} = 720 V,		39		ns
Rise Time	t,	I _D = 60 A, R _G =	= 2.5 Ω,		52	1	1

Turn-On Delay Time	^t d(ON)	$V_{GS} = -5/15 \text{ V}, V_{DS} = 720 \text{ V},$	39	ns
Rise Time	t _r	$I_D = 60 \text{ A}, R_G = 2.5 \Omega,$ Inductive Load	52	
Turn-Off Delay Time	t _{d(OFF)}		58	
Fall Time	t _f]	13	
Turn-On Switching Loss	E _{ON}]	1551	μJ
Turn-Off Switching Loss	E _{OFF}		179	
Total Switching Loss	E _{TOT}		1730	

DRAIN-SOURCE DIODE CHARACTERISTICS

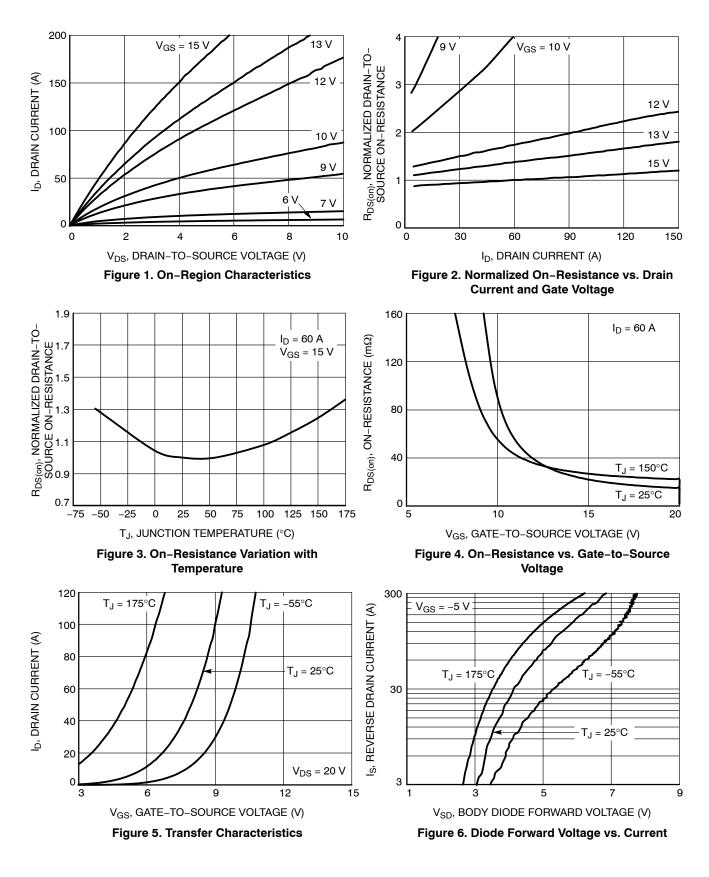
Continuous Drain-Source Diode Forward Current	I _{SD}	V_{GS} = -5 V, T_{J} = 25°C		148	A
Pulsed Drain-Source Diode Forward Current (Note 3)	I _{SDM}	V_{GS} = -5 V, T_{J} = 25°C		448	A
Forward Diode Voltage	V _{SD}	V_{GS} = –5 V, I_{SD} = 30 A, T_J = 25°C	3.7		V

Table 2. ELECTRICAL CHARACTERISTICS (T_J = 25° C unless otherwise stated) (continued)

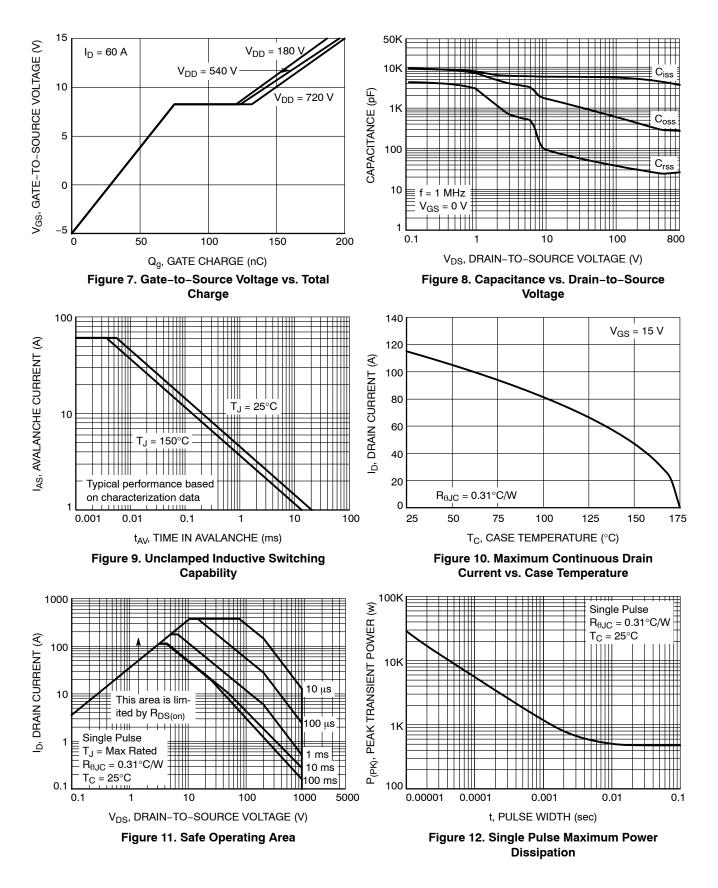
Parameter	Symbol	Test Condition	Min	Тур	Max	Unit		
DRAIN-SOURCE DIODE CHARACTERISTICS								
Reverse Recovery Time	t _{RR}	V _{GS} = -5/15 V, I _{SD} = 60 A, dI _S /dt = 1000 A/µs, V _{DS} = 720 V		28		ns		
Reverse Recovery Charge	Q _{RR}	αι _S /αt = 1000 Α/μs, v _{DS} = 720 v		186		nC		
Reverse Recovery Energy	E _{REC}	1		4		μJ		
Peak Reverse Recovery Current	I _{RRM}	1		14		А		
Charge Time	Та]		17		ns		
Discharge Time	Tb	1		11		ns		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

TYPICAL CHARACTERISTICS



TYPICAL CHARACTERISTICS (continued)



TYPICAL CHARACTERISTICS (continued)

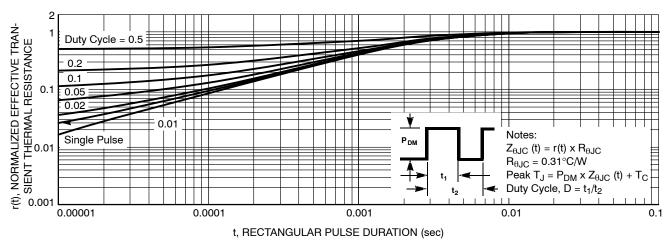
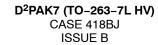


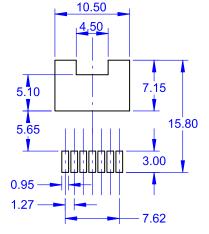
Figure 13. Junction-to-Ambient Transient Thermal Response Curve

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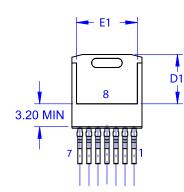




Α F L1 D b2 е h \oplus aaa B A M



LAND PATTERN RECOMMENDATION



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GENERIC **MARKING DIAGRAM***

XXXXXXXXX AYWWG
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XXXX = Specific Device Code А = Assembly Location Y = Year

- WW = Work Week
- G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

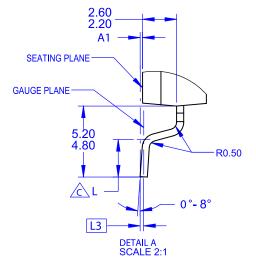
B	A
c2 —	
•	
H	
	A

NOTES:

A. PACKAGE CONFORMS TO JEDEC TO-263 VARIATION CB EXCEPT WHERE NOTED. B. ALL DIMENSIONS ARE IN MILLIMETERS.

C OUT OF JEDEC STANDARD VALUE. D. DIMENSION AND TOLERANCE AS PER ASME Y14.5-2009. E. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH AND TIE BAR PROTRUSIONS.

DIM	MILLIMETERS				
	MIN	NOM	MAX		
Α	4.30	4.50	4.70		
A1	0.00	0.10	0.20		
b2	0.60	0.70	0.80		
b	0.51	0.60	0.70		
С	0.40	0.50	0.60		
c2	1.20	1.30	1.40		
D	9.00	9.20	9.40		
D1	6.15	6.80	7.15		
E	9.70	9.90	10.20		
E1	7.15	7.65	8.15		
е	~	1.27	~		
Н	15.10	15.40	15.70		
L	2.44	2.64	2.84		
L1	1.00	1.20	1.40		
L3	~	0.25	~		
aaa	~	~	0.25		



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